Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/602,570	GRINCHUK ET AL.
Examiner	Art Unit
Sun J. Lin	2825

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Class	Subclass	Date	Examiner
716	18	2/16/2005	JSL
716	2	2/16/2005	JSL
716	1	2/16/2005	JSL
716	7	2/16/2005	JSL
326	104	2/16/2005	JSL
326	10	2/16/2005	JSL
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT		 )
	DATE	EXMR
EAST [USPAT;US- PGPUB;UPO;JPO;DERWENT;IBM_T DB]	2/16/2005	JSL
IEEE	2/16/2005	JSL
GOOGLE	2/16/2005	JSL
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